INTERNATIONAL STANDARD

ISO 11452-1

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Road vehicles — Electrical disturbances by narrowband radiated electromagnetic energy — Component test methods —

Part 1: General and definitions

Véhicules routiers — Perturbations électriques par rayonnement d'énergie électromagnétique en bande étroite — Méthodes d'essai d'un composant —

Partie 1: Généralités et définitions

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Contents

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

International Standard ISO 11452-1 was prepared by Technical Committee ISO/TC 22, *Road vehicles*, Subcommittee SC 3, *Electrical and electronic equipment.*

ISO 11452 consists of the following parts, under the general title *Road vehicles — Electrical disturbances by narrowband radiated electromagnetic energy — Component test methods*:

- — *Part 1: General and definitions*
- — *Part 2: Absorber-lined chamber*
- — *Part 3: Transverse electromagnetic mode (TEM) cell*
- — *Part 4: Bulk current injection (BCI)*
- — *Part 5: Stripline*
- — *Part 6: Parallel plate antenna*
- — *Part 7: Direct radio frequency (RF) power injection*

Annex A forms an integral part of this part of ISO 11452. Annex B is for information only.

Introduction

During recent years, an increasing number of electronic devices have been introduced into vehicle designs in order to control, monitor and display various functions. It is necessary to consider the electrical and electromagnetic environment in which these devices are required to operate.

Electrical and radio-frequency disturbances occur during normal operation of many items of motor vehicle equipment. They are generated over a wide frequency range with various electrical characteristics and may be distributed to on-board electronic devices and systems by conduction and/or radiation.

Narrowband signals generated from sources on-board or off-board the vehicle could also be coupled into the electrical/electronic system, affecting the normal performance of electronic devices. Sources of narrowband electromagnetic disturbances are mobile radios, broadcast transmitters, etc.

The characteristics of the immunity of components to radiated disturbances have to be established. It is the intention of ISO 11452 to provide various test methods for the analysis of component electromagnetic compatibility (EMC). Not all test methods need to be used for a given device under test. For example, stripline, transverse electromagnetic mode (TEM) cell and parallel plate test methods provide very similar exposure to the device under test. Only the tests necessary to replicate the use and mounting location of the device under test need to be included in the test plan. This will help to ensure a technically and economically optimized design for potentially susceptible components and systems.

It should also be noted that ISO 11452 is not intended to be a product specification and cannot function as one (see A.2). Therefore, no specific values for the test severity level are given, since they should be determined for each component by the vehicle manufacturer and supplier(s).

Protection from potential disturbances has to be considered as a part of total vehicle validation (as described in ISO 11451) which covers vehicle test methods. It is important to know the correlation between laboratory and vehicle tests.

Road vehicles — Electrical disturbances by narrowband radiated electromagnetic energy — Component test methods —

Part 1:
General and definitions

1 Scope

This part of ISO 11452 defines basic terms used in the various parts of ISO 11452 for electrical disturbances by narrowband radiated electromagnetic energy in component test methods. It also gives general information relating to, and common to, all parts of ISO 11452. It applies to all types of road vehicles regardless of the propulsion system (e.g. spark-ignition engine, diesel engine, electric motor).

Parts 2 to 7 of ISO 11452 present various test methods to evaluate the immunity of components, used in road vehicles, to radiated disturbances. The electromagnetic disturbances considered in these parts are limited to continuous narrowband electromagnetic energy. Typical severity levels are included in an annex to each part.

The various parts of ISO 11452 allow a wide frequency range (10 kHz to 18 000 MHz) for immunity testing of components.

2 Normative reference

The following standard contains provisions which, through reference in this text, constitute provisions of this part of ISO 11452. At the time of publication, the edition indicated was valid. All standards are subject to revision, and parties to agreements based on this part of ISO 11452 are encouraged to investigate the possibility of applying the most recent edition of the standard indicated below. Members of IEC and ISO maintain registers of currently valid International Standards.

ISO 11451-1:1995, *Road vehicles — Electrical disturbances by narrowband radiated electromagnetic energy — Vehicle test methods — Part 1: General and definitions.*

3 Definitions

For the purposes of all parts of ISO 11452, the following definitions apply.

3.1 electromagnetic compatibility (EMC): Ability of an equipment or system to function satisfactorily in its electromagnetic environment without introducing intolerable electromagnetic disturbances to anything in that environment.

[Adapted from IEC 50:1990-161-01-07]

3.2 electromagnetic disturbance: Any electromagnetic phenomenon which may degrade the performance of a device, equipment or system, or adversely affect living or inert matter.

[Adapted from IEC 50:1990-161-01-05]

3.3 electromagnetic interference (EMI): Degradation of the performance of equipment, transmission channel or system caused by an electromagnetic disturbance.

[Adapted from IEC 50:1990-161-01-06]

3.4 degradation (of performance): Undesired departure in the operational performance of any device, equipment or system from its intended performance.

[Adapted from IEC 50:1990-161-01-19]

3.5 immunity (to a disturbance): Ability of a device, equipment or system to perform without degradation in the presence of an electromagnetic disturbance.

[Adapted from IEC 50:1990-161-01-20]

3.6 (electromagnetic) susceptibility: Inability of a device, equipment or system to perform without degradation in the presence of an electromagnetic disturbance.

[Adapted from IEC 50:1990-161-01-21]

3.7 immunity level: Maximum level of a given electromagnetic disturbance incident on a particular device, equipment or system for which it remains capable of operating at a required degree of performance.

[Adapted from IEC 50:1990-161-03-14]

3.8 narrowband emission: Emission which has a bandwidth less than that of a particular measuring apparatus or receiver.

[Adapted from IEC 50:1990-161-06-13]

3.9 broadband emission: Emission which has a bandwidth greater than that of a particular measuring apparatus or receiver.

[Adapted from IEC 50:1990-161-06-11]

3.10 (electromagnetic) radiation:

(1) Phenomenon by which energy in the form of electromagnetic waves emanates from a source into space.

(2) Energy transferred through space in the form of electromagnetic waves.

[Adapted from IEC 50:1990-161-01-10]

3.11 coupling: Means or device for transferring power between systems.

[Adapted from IEC 50:1982-726-14-01]

3.12 standing wave ratio (SWR); voltage standing wave ratio (VSWR): Ratio, along a transmission line, of a maximum to an adjacent minimum magnitude of a particular field component of a standing wave.

[Adapted from IEC 50:1982-726-07-09]

3.13 polarization (of a wave or field vector): Property of a sinusoidal electromagnetic wave or field vector defined at a fixed point in space by the direction of the electric field strength vector or of any specified field vector; when this direction varies with time the property may be characterized by the locus described by the extremity of the considered field vector.

[Adapted from IEC 50:1982-726-04-01]

3.14 shielded enclosure: Mesh or sheet metallic housing designed expressly for the purpose of separating electromagnetically the internal and external environment.

[Adapted from IEC 50:1990-161-04-37]

3.15 ground (reference) plane: Flat conductive surface whose potential is used as a common reference.

[Adapted from IEC 50:1990-161-04-36]

3.16 stripline: Terminated transmission line consisting of two parallel plates between which a wave is propagated in the transverse electromagnetic mode to produce a specified field for testing purposes.

[Adapted from IEC 50:1990-161-04-31]

3.17 TEM mode: Mode in which both the longitudinal components of the electric and magnetic field strength vectors are everywhere zero.

[Adapted from IEC 50:1982-726-03-08]

3.18 TEM cell: Enclosed system, often a rectangular coaxial line, in which a wave is propagated in the transverse electromagnetic mode to produce a specified field for testing purposes.

[Adapted from IEC 50:1990-161-04-32]

3.19 current probe: Device for measuring the current in a conductor without interrupting the conductor and without introducing significant impedance into the associated circuits.

[Adapted from IEC 50:1990-161-04-35]

3.20 directional coupler: Four-port device consisting of two transmission lines coupled together in such a manner that a single travelling wave in any one transmission line will induce a single travelling wave in the other, the direction of propagation of the latter wave being dependent upon that of the former.

[Adapted from IEC 50:1982-726-14-02]

3.21 artificial network (AN): Network inserted in the supply leads of apparatus to be tested which provides, in a given frequency range, a specified load impedance for the measurement of disturbance voltages and which isolates the apparatus from the power supply in that frequency range.

NOTE 1 This term is used in all parts of ISO 11452 except ISO 11452-7.

3.22 parallel plate antenna: Electric field generating antenna with a set of parallel arms.

3.23 absorber-lined chamber: Shielded room with absorbing material on its internal reflective surfaces.

NOTE 2 The floor may optionally be excluded.

3.24 bulk current: Total amount of common mode current in a harness.

3.25 broadband artificial network (BAN): Device that presents a controlled impedance to the device under test over a specified frequency range while allowing the device under test to be interfaced to its support system, used in power, signal and control lines.

NOTE 3 This term is used in ISO 11452-7.

3.26 amplitude modulation (AM): Process by which the amplitude of a carrier wave is varied following a specified law, resulting in an AM signal.

3.27 forward power: Power supplied by the output of an amplifier or generator.

3.28 reflected power: Power reflected by the load due to impedance mismatch between the transmission line and the load.

3.29 net power: Forward power minus reflected power.

4 General aim and practical use

The recommended test methods, procedures, test instrumentation and levels presented in all parts of ISO 11452 are intended to facilitate component specification for electrical disturbance by narrowband radiated electromagnetic energy. A basis is provided for mutual agreement between vehicle manufacturers and component suppliers which is intended to assist rather than restrict them.

Certain devices are particularly susceptible to some characteristics of electromagnetic disturbance, such as frequency, severity level, type of coupling or modulation.

Electronic devices are sometimes more susceptible to modulated, as opposed to unmodulated, radio-frequency (RF) signals. The reason is that high-frequency disturbances may be demodulated by semiconductors. In the case of continuous wave (CW) signals this leads to a continuous shift of, for example, a voltage; in the case of AM signals the resulting low-frequency fluctuations may be interpreted as wanted signals (e.g. speed information) and thus disturb the function of the device under test more severely.

A single standard test may not reveal all the necessary information about the device under test. It is necessary to anticipate the appropriate test conditions, select applicable parts of ISO 11452 and define function performance objectives. The main characteristics of each test method in ISO 11452, parts 2 to 7, are presented in table 1.

5 Test procedures

The common characteristics for ISO 11452, parts 2 to 7, are described in this clause.

NOTE 4 The use of the same parameters for vehicle test methods as described in the corresponding parts of ISO 11451 will achieve better correlation.

5.1 Test conditions

The following test conditions are common to ISO 11452, parts 2 to 7:

— test temperature and supply voltage;

— modulation;

— dwell time;

— frequency steps.

Table 1 — Main characteristics of test methods in ISO 11452, Parts 2 to 7

	Applicable frequency range MHz	Field coupling mechanism	Test severity parameter and unit	Restrictions
Part 2: Absorber-lined chamber	200 to 18 000	to device under test and wiring harness	Electric field (V/m)	Absorber-lined chamber required
Part 3: TEM cell	0,01 to 200	to device under test and wiring harness	Electric field (V/m)	Device under test and/or wiring harness size limitation
Part 4: Bulk current injection	1 to 400	to wiring harness	Current (mA)	Shielded room recommended
Part 5: Stripline	0,01 to 200	to wiring harness (and device under test)	Electric field (V/m)	Shielded room recommended (device under test size limitation)
Part 6: Parallel plate antenna	0,01 to 200	to device under test and wiring harness	Electric field (V/m)	Shielded room recommended
Part 7: Direct RF power injection	0,25 to 400	to wiring harness	Power (W)	Influence of isolator on device under test behaviour

5.1.1 Test temperature and supply voltage

The ambient temperature during the test shall be (23 ± 5) °C.

The supply voltage during the test shall be (13,5 ± 0,5) V for 12 V electrical systems and (27 ± 1) V for 24 V electrical systems.

If other values are agreed by the users of ISO 11452, the values shall be recorded in the test report.

5.1.2 Modulation

The device under test determines the type and frequency of modulation. If no values are agreed between the users of ISO 11452, the following shall be used:

— no modulation (CW);

— 1 kHz sine-wave amplitude modulation (AM) of 80 %.

5.1.3 Dwell time

At each frequency, the device under test shall be exposed to the test level for the minimum response time needed to control it. In all cases, this minimum time of exposure shall not be less than 2 s.

5.1.4 Frequency step sizes

All the tests described in ISO 11452 shall be conducted with linear frequency step sizes not greater than those specified in table 2 (according to the applicable frequency range stated in the relevant part of ISO 11452).

Table 2 — Frequency step sizes

Frequency band MHz	Maximum frequency step size MHz
>0,01 to ⩽0,1	0,01
>0,1 to ⩽1	0,1
>1 to ⩽10	1
>10 to ⩽200	2
>200 to ⩽1 000	20
>1 000 to ⩽18 000	200

Alternatively logarithmic frequency steps, with the same minimum number of frequency steps in each

frequency band, may be used. The values, as agreed by the users of ISO 11452, shall be documented in the test report.

If it appears that the susceptibility thresholds of the device under test are very near the chosen test level, these frequency step sizes should be reduced in the frequency range concerned in order to find the minimum susceptibility thresholds.

5.2 Test methods

5.2.1 Methodologies

Some parts of ISO 11452 present two test methods.

5.2.1.1 Substitution method

The substitution method is based upon the use of net power as the reference parameter used for calibration and test.

In this method, the specific test level (electric field, current, voltage or power) shall be be calibrated prior to the actual testing.

The test is conducted by subjecting the device under test to the test signals based on the calibrated values as predetermined in the test plan.

Measurements using the substitution method can be affected by coupling between the antenna and the device under test as well as by reflected energy. During the test, the net power shall be maintained relative to the calibration point up to a limit of 2 dB increase in forward power. If the forward power has to be increased by 2 dB or more, this shall be indicated in the test report.

NOTE 5 If the standing wave ratio (SWR) in the test system is less than 1,2:1, then forward power may be used as the reference parameter to establish the test level.

5.2.1.2 Closed-loop levelling method

During the actual test with the device under test, the test level (electric field, voltage, current or power) is measured by a calibrated device and fed back to the signal generator either to increase or to decrease the test level until the predetermined value is achieved.

5.2.2 Calibration

Calibration shall be performed in accordance with individual test method requirements. The test level versus frequency data shall be established using a CW signal. The method and results for each calibration shall also be documented in the test report.

5.2.3 Test procedure

The test procedure shall apply the following specifications.

5.2.3.1 At each frequency increase the level, linearly or logarithmically, up to the chosen test level. The rate of increase of the test level shall be controlled so that excessive overshoot does not occur. The test level parameter (see annex A regarding test level specification) is

— the net power, P_{net}, related to the test signal severity level, for the substitution method:

$$P_{net} = P_{net,\,cal} \left(\frac{l_{tss}}{l_{cal}} \right)^{k}$$

where

$P_{net,\,cal}$ is the net power by calibration;

l_{tss} is the test signal severity level;

l_{cal} is the calibration level;

k is a factor, equal to 1 for power test levels and equal to 2 for electromagnetic field, current or voltage test levels.

— the test severity level for the closed-loop levelling method.

Table 3 gives the CW and AM test levels for the substitution method and for the closed-loop levelling method.

Both of these methods use a constant peak test level for CW and AM tests. The relationship between AM net power and CW calibrated net power results from this principle (see annex B).

5.2.3.2 Maintain the test level for the minimum response time needed to control the device under test. This minimum time of exposure shall be greater than or equal to 2 s.

5.2.3.3 Decrease the test level by at least 20 dB before moving to the next frequency.

The rate of decrease of the level shall be controlled to avoid unreproducible susceptibilities.

NOTE 6 Turning off the frequency generator may cause unreproducible susceptibilities of the device under test.